
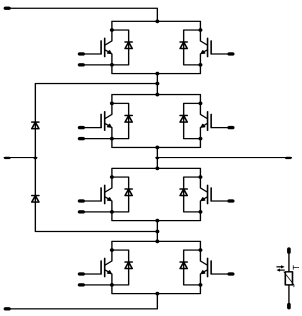




Vincotech

<i>flow NPC 1</i>	650 V / 150 A
<div style="background-color: #eee; padding: 2px; margin-bottom: 5px;">Features</div> <ul style="list-style-type: none"> Neutral-point-Clamped inverter Compact <i>flow 1</i> housing Low Inductance Layout 	<div style="background-color: #eee; padding: 2px; margin-bottom: 5px;">flow 1 12mm housing</div> 
<div style="background-color: #eee; padding: 2px; margin-bottom: 5px;">Target Applications</div> <ul style="list-style-type: none"> UPS Motor Drive Solar inverters 	<div style="background-color: #eee; padding: 2px; margin-bottom: 5px;">Schematic</div> 
<div style="background-color: #eee; padding: 2px; margin-bottom: 5px;">Types</div> <ul style="list-style-type: none"> 10-PY07NIB150SG-M136F38Y 	

Maximum Ratings

$T_j = 25\text{ °C}$, unless otherwise specified

Parameter	Symbol	Condition	Value	Unit
Buck IGBT				
Collector-emitter breakdown voltage	V_{CE}		650	V
DC collector current	I_C	$T_j = T_{jmax}$ $T_s = 80\text{ °C}$	128	A
Repetitive peak collector current	I_{CRM}	t_p limited by T_{jmax}	450	A
Power dissipation	P_{tot}	$T_j = T_{jmax}$ $T_s = 80\text{ °C}$	279	W
Gate-emitter peak voltage	V_{GE}		±20	V
Short circuit ratings	t_{SC} V_{CC}	$T_j \leq 150\text{ °C}$ $V_{GE} = 15\text{ V}$	5 400	μs V
Maximum Junction Temperature	T_{jmax}		175	°C
Buck Diode				
Peak Repetitive Reverse Voltage	V_{RRM}		650	V
DC forward current	I_F	$T_j = T_{jmax}$ $T_s = 80\text{ °C}$	125	A
Diode surge non repetitive forward current	I_{FSM}	$t_p = 10\text{ ms}$, sine half wave $T_j = 100\text{ °C}$	1280	A
Power dissipation	P_{tot}	$T_j = T_{jmax}$ $T_s = 80\text{ °C}$	241	W
Maximum Junction Temperature	T_{jmax}		175	°C

**Maximum Ratings** $T_j = 25\text{ °C}$, unless otherwise specified

Parameter	Symbol	Condition	Value	Unit
Boost IGBT				
Collector-emitter breakdown voltage	V_{CE}		600	V
DC collector current	I_C	$T_j = T_{jmax}$ $T_s = 80\text{ °C}$	173	A
Repetitive peak collector current	I_{CRM}	t_p limited by T_{jmax}	450	A
Power dissipation	P_{tot}	$T_j = T_{jmax}$ $T_s = 80\text{ °C}$	324	W
Gate-emitter peak voltage	V_{GE}		± 20	V
Short circuit ratings	t_{SC} V_{CC}	$T_j \leq 150\text{ °C}$ $V_{GE} = 15\text{ V}$	6 360	μs V
Maximum Junction Temperature	T_{jmax}		175	$^{\circ}\text{C}$

Boost Inverse Diode

Peak Repetitive Reverse Voltage	V_{RRM}		600	V
DC forward current	I_F	$T_j = T_{jmax}$ $T_s = 80\text{ °C}$	124	A
Repetitive peak forward current	I_{FRM}	t_p limited by T_{jmax}	200	A
Power dissipation	P_{tot}	$T_j = T_{jmax}$ $T_s = 80\text{ °C}$	204	W
Maximum Junction Temperature	T_{jmax}		175	$^{\circ}\text{C}$

Boost Diode

Peak Repetitive Reverse Voltage	V_{RRM}		650	V
DC forward current	I_F	$T_j = T_{jmax}$ $T_s = 80\text{ °C}$	120	A
Repetitive peak forward current	I_{FRM}	t_p limited by T_{jmax}	200	A
Power dissipation	P_{tot}	$T_j = T_{jmax}$ $T_s = 80\text{ °C}$	203	W
Maximum Junction Temperature	T_{jmax}		175	$^{\circ}\text{C}$

Thermal Properties

Storage temperature	T_{stg}		-40...+125	$^{\circ}\text{C}$
Operation temperature under switching condition	T_{op}		-40...+($T_{jmax} - 25$)	$^{\circ}\text{C}$

Isolation Properties

Isolation voltage	V_{is}	$t = 2\text{ s}$ DC Test Voltage	4000	V
Creepage distance			min 12,7	mm
Clearance			min 12,7	mm
Comparative Tracking Index	CTI		>200	



Characteristic Values

Parameter	Symbol	Conditions					Value			Unit	
		V_{GE} [V]	V_{GS} [V]	V_r [V]	V_{CE} [V]	V_{DS} [V]	I_C [A]	I_F [A]	I_D [A]		T_j [°C]

Buck IGBT

Gate emitter threshold voltage	$V_{GE(th)}$	$V_{CE} = V_{GE}$				0,0024	25		4,2	5,1	5,6	V
Collector-emitter saturation voltage	$V_{CE(sat)}$		15			150	25 150		1,38	1,94 2,26	2,22	V
Collector-emitter cut-off current incl. Diode	I_{CES}		0	650			25				0,0076	mA
Gate-emitter leakage current	I_{GES}		20	0			25				300	nA
Integrated Gate resistor	R_{gint}									none		Ω
Turn-on delay time	$t_{d(on)}$						25 150			147 149		ns
Rise time	t_r						25 150			30 34		
Turn-off delay time	$t_{d(off)}$	$R_{gon} = 4 \Omega$	± 15	350	150		25 150			197 219		
Fall time	t_f	$R_{goff} = 4 \Omega$					25 150			18 27		
Turn-on energy loss	E_{on}						25 150			1,53 2,45		mWs
Turn-off energy loss	E_{off}						25 150			1,69 2,68		
Input capacitance	C_{ies}									9240		pF
Output capacitance	C_{oss}	$f = 1 \text{ MHz}$	0	25			25			480		
Reverse transfer capacitance	C_{rss}									274		
Gate charge	Q_G		15	480	150		25			940		nC
Thermal resistance junction to sink	$R_{th(j-s)}$	phase-change material $\lambda = 3,4 \text{ W/mK}$								0,34		K/W

Buck Diode

Diode forward voltage	V_F					160	25 150			1,67 2,01	1,7	V
Reverse leakage current	I_r			650			25				160	μA
Peak reverse recovery current	I_{RRM}						25 150			104 157		A
Reverse recovery time	t_{rr}						25 150			59 97		ns
Reverse recovered charge	Q_{rr}	$R_{gon} = 4 \Omega$	± 15	350	150		25 150			5 10		μC
Peak rate of fall of recovery current	$(di_{rr}/dt)_{max}$						25 150			6885 3093		A/ μs
Reverse recovered energy	E_{rec}						25 150			0,92 2,07		mWs
Thermal resistance junction to sink	$R_{th(j-s)}$	phase-change material $\lambda = 3,4 \text{ W/mK}$								0,39		K/W



Characteristic Values

Parameter	Symbol	Conditions					Value			Unit			
		V_{GE} [V]	V_{GS} [V]	V_r [V]	V_{CE} [V]	V_{DS} [V]	I_C [A]	I_F [A]	I_D [A]		T_j [°C]	Min	Typ
Boost IGBT													
Gate emitter threshold voltage	$V_{GE(th)}$	$V_{CE} = V_{GE}$				0,0024	25			5	5,8	6,5	V
Collector-emitter saturation voltage	V_{CESat}		15			150	25 150			1,05	1,46 1,65	1,85	V
Collector-emitter cut-off incl diode	I_{CES}		0	600			25					0,0076	mA
Gate-emitter leakage current	I_{GES}		20	0			25					1200	nA
Integrated Gate resistor	R_{gint}						25				none		Ω
Turn-on delay time	$t_{d(on)}$	$R_{goff} = 4 \Omega$ $R_{gon} = 4 \Omega$	± 15	350	150		25				149		ns
Rise time	t_r						150				151		
Turn-off delay time	$t_{d(off)}$						25				31		
Fall time	t_f						150				36		
Turn-on energy loss	E_{on}						25				220		
Turn-off energy loss	E_{off}						150				245		
Turn-on energy loss	E_{on}					25				1,77		2,38	mWs
Turn-off energy loss	E_{off}					25				4,26		5,95	mWs
Input capacitance	C_{ies}										9240		pF
Output capacitance	C_{oss}	$f = 1 \text{ MHz}$	0	25		25					576		
Reverse transfer capacitance	C_{rss}										274		
Gate charge	Q_G		15	480	150						940		nC
Thermal resistance junction to sink	$R_{th(j-s)}$	phase-change material $\lambda = 3,4 \text{ W/mK}$									0,29		K/W
Boost Inverse Diode													
Diode forward voltage	V_F					100	25 150			1,20	1,77 1,54	1,90	V
Thermal resistance junction to sink	$R_{th(j-s)}$	phase-change material $\lambda = 3,4 \text{ W/mK}$									0,46		K/W
Boost Diode													
Diode forward voltage	V_F					100	25 150			1,2	1,77 1,57	1,9	V
Reverse leakage current	I_r			650			25					48	μA
Peak reverse recovery current	I_{RRM}	$R_{goff} = 4 \Omega$	± 15	350	150		25				82		A
Reverse recovery time	t_{rr}						150				114		
Reverse recovered charge	Q_{rr}						25				133		
Peak rate of fall of recovery current	$(di_{rr}/dt)_{max}$						150				290		
Reverse recovery energy	E_{rec}						25				6		
							150				13		
Reverse recovery energy	E_{rec}					25				1,65		3,68	mWs
Thermal resistance junction to sink	$R_{th(j-s)}$	phase-change material $\lambda = 3,4 \text{ W/mK}$									0,47		K/W
Thermistor													
Rated resistance	R						25				21511		Ω
Deviation of R_{100}	$\Delta_{R/R}$	$R_{100} = 1486 \Omega$					100			-4,5		+4,5	%
Power dissipation	P						25				210		mW
Power dissipation constant							25				3,5		mW/K
B-value	$B_{(25/50)}$						25				3884		K
B-value	$B_{(25/100)}$	Tol. $\pm 1\%$					25				3964		K
Vincotech NTC Reference												F	

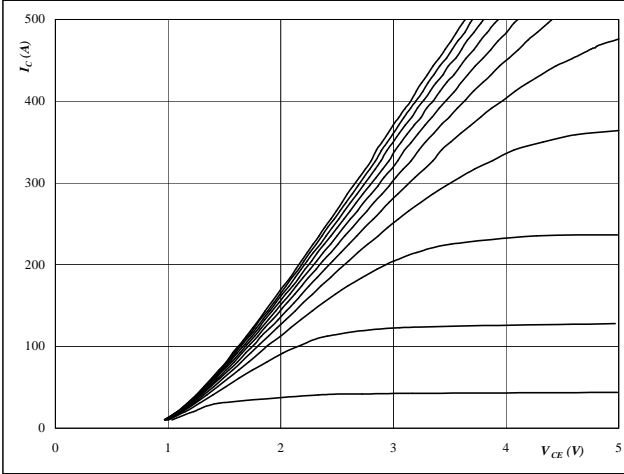


Buck

figure 1. IGBT

Typical output characteristics

$I_C = f(V_{CE})$

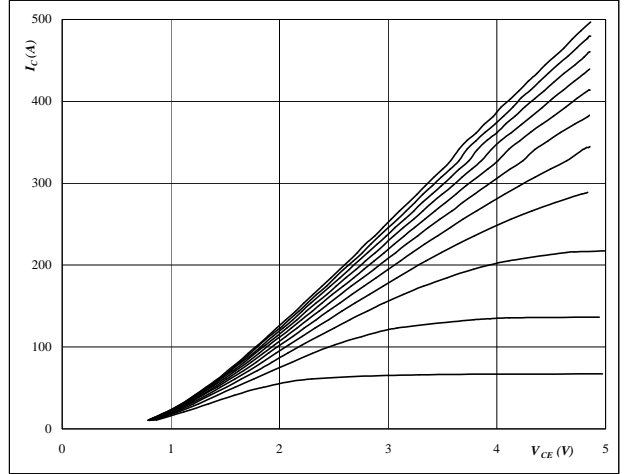


At
 $t_p = 350 \mu s$
 $T_j = 25 \text{ } ^\circ C$
 V_{GE} from 7 V to 17 V in steps of 1 V

figure 2. IGBT

Typical output characteristics

$I_C = f(V_{CE})$

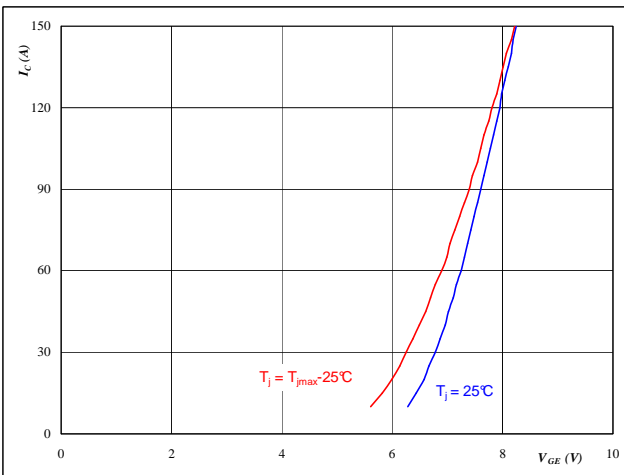


At
 $t_p = 350 \mu s$
 $T_j = 150 \text{ } ^\circ C$
 V_{GE} from 7 V to 17 V in steps of 1 V

figure 3. IGBT

Typical transfer characteristics

$I_C = f(V_{GE})$

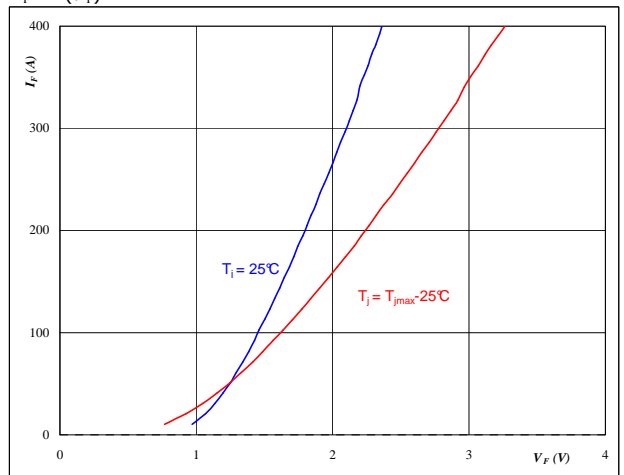


At
 $t_p = 350 \mu s$
 $V_{CE} = 10 V$

figure 4. FWD

Typical diode forward current as a function of forward voltage

$I_F = f(V_F)$



At
 $t_p = 350 \mu s$

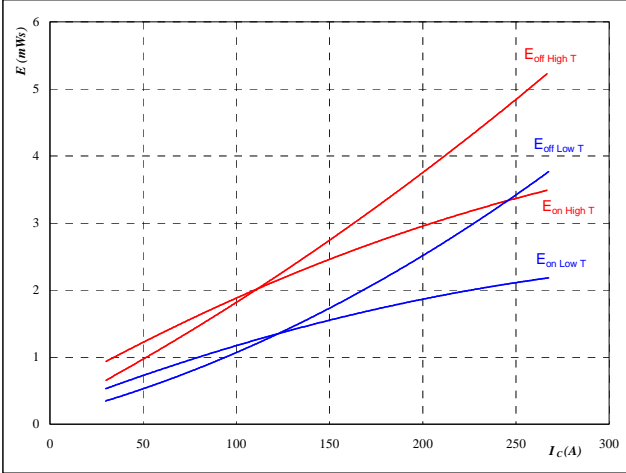


Buck

figure 5. IGBT

**Typical switching energy losses
as a function of collector current**

$E = f(I_C)$



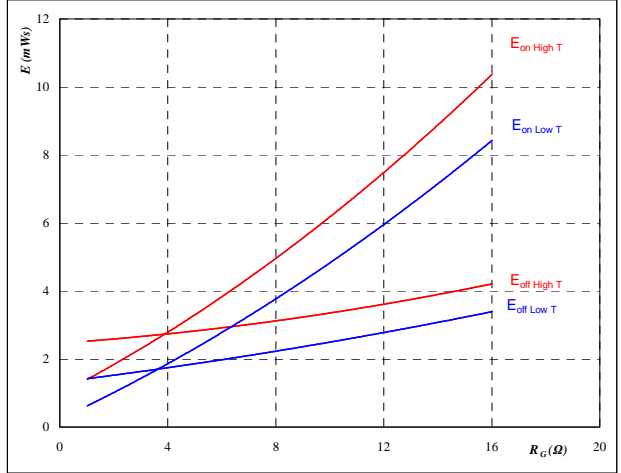
With an inductive load at

$T_j =$	25/150	°C
$V_{CE} =$	350	V
$V_{GE} =$	±15	V
$R_{gon} =$	4	Ω
$R_{goff} =$	4	Ω

figure 6. IGBT

**Typical switching energy losses
as a function of gate resistor**

$E = f(R_G)$



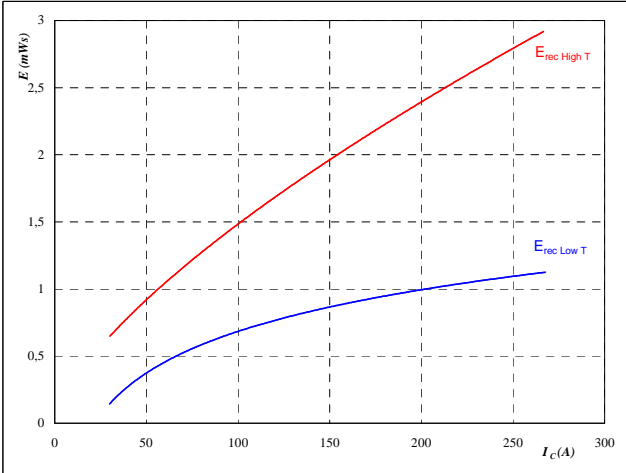
With an inductive load at

$T_j =$	25/150	°C
$V_{CE} =$	350	V
$V_{GE} =$	±15	V
$I_C =$	150	A

figure 7. FWD

**Typical reverse recovery energy loss
as a function of collector current**

$E_{rec} = f(I_C)$



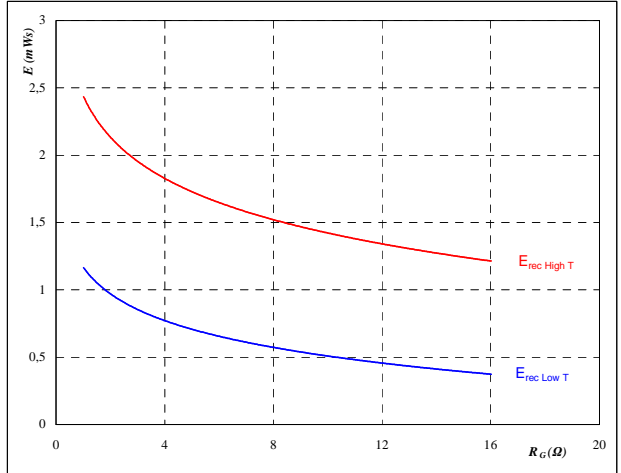
With an inductive load at

$T_j =$	25/150	°C
$V_{CE} =$	350	V
$V_{GE} =$	±15	V
$R_{gon} =$	4	Ω

figure 8. FWD

**Typical reverse recovery energy loss
as a function of gate resistor**

$E_{rec} = f(R_G)$



With an inductive load at

$T_j =$	25/150	°C
$V_{CE} =$	350	V
$V_{GE} =$	±15	V
$I_C =$	150	A

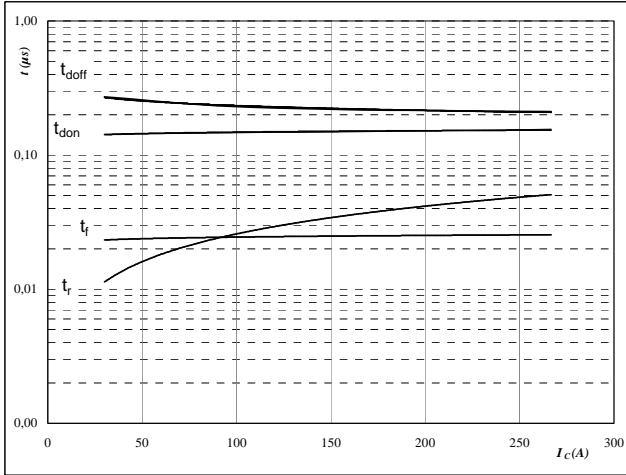


Buck

figure 9. IGBT

Typical switching times as a function of collector current

$$t = f(I_C)$$



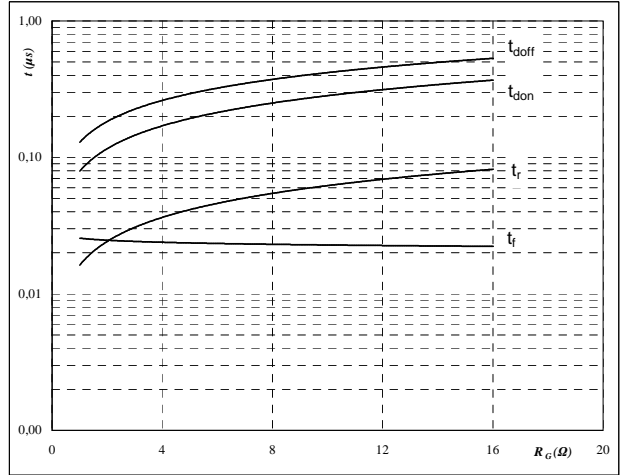
With an inductive load at

$T_j =$	150	°C
$V_{CE} =$	350	V
$V_{GE} =$	±15	V
$R_{gon} =$	4	Ω
$R_{goff} =$	4	Ω

figure 10. IGBT

Typical switching times as a function of gate resistor

$$t = f(R_G)$$



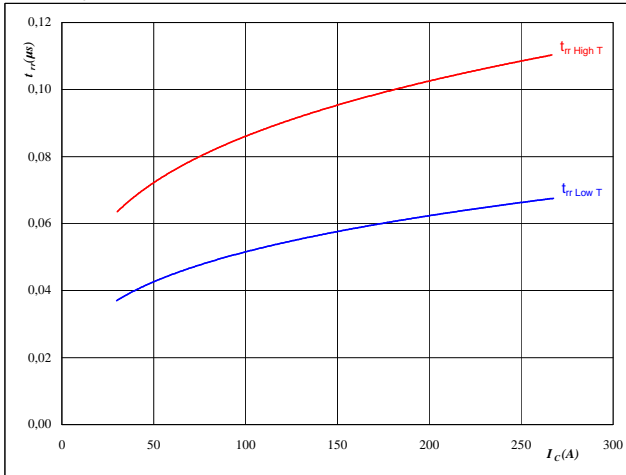
With an inductive load at

$T_j =$	150	°C
$V_{CE} =$	350	V
$V_{GE} =$	±15	V
$I_C =$	150	A

figure 11. FWD

Typical reverse recovery time as a function of collector current

$$t_{rr} = f(I_C)$$



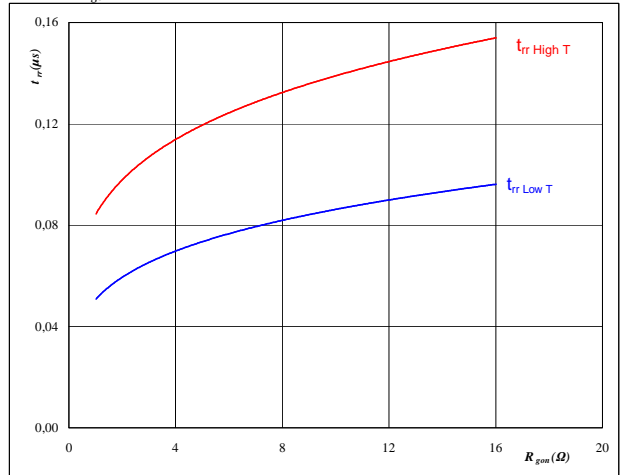
At

$T_j =$	25/150	°C
$V_{CE} =$	350	V
$V_{GE} =$	±15	V
$R_{gon} =$	4	Ω

figure 12. FWD

Typical reverse recovery time as a function of IGBT turn on gate resistor

$$t_{rr} = f(R_{gon})$$



At

$T_j =$	25/150	°C
$V_R =$	350	V
$I_F =$	150	A
$V_{GE} =$	±15	V

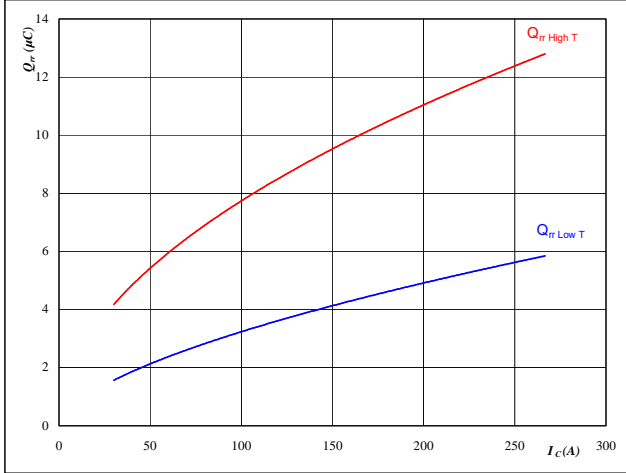


Buck

figure 13. FWD

Typical reverse recovery charge as a function of collector current

$$Q_{rr} = f(I_C)$$

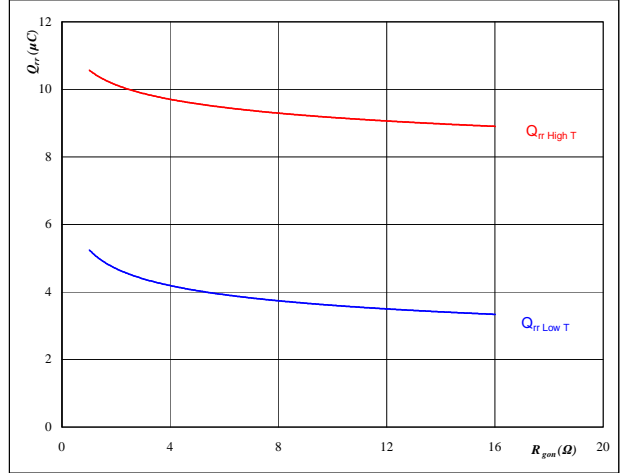


At
 $T_j = 25/150$ °C
 $V_{CE} = 350$ V
 $V_{GE} = \pm 15$ V
 $R_{gon} = 4$ Ω

figure 14. FWD

Typical reverse recovery charge as a function of IGBT turn on gate resistor

$$Q_{rr} = f(R_{gon})$$

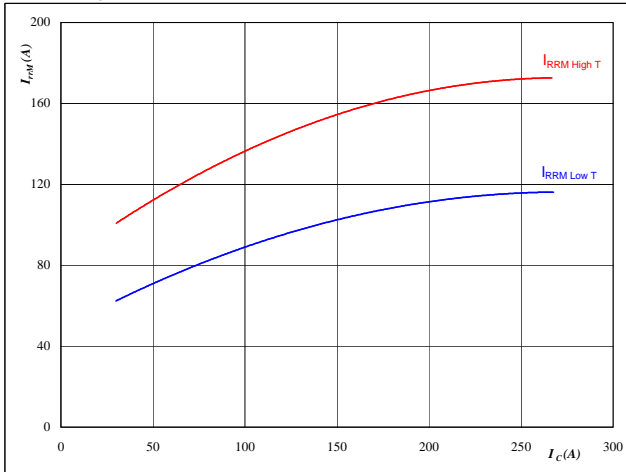


At
 $T_j = 25/150$ °C
 $V_R = 350$ V
 $I_F = 150$ A
 $V_{GE} = \pm 15$ V

figure 15. FWD

Typical reverse recovery current as a function of collector current

$$I_{RRM} = f(I_C)$$

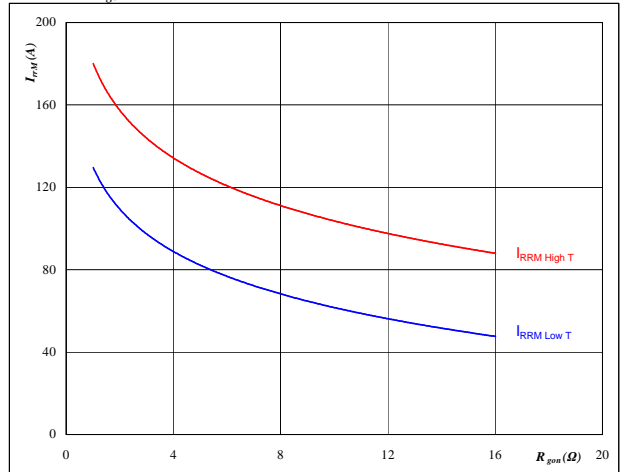


At
 $T_j = 25/150$ °C
 $V_{CE} = 350$ V
 $V_{GE} = \pm 15$ V
 $R_{gon} = 4$ Ω

figure 16. FWD

Typical reverse recovery current as a function of IGBT turn on gate resistor

$$I_{RRM} = f(R_{gon})$$



At
 $T_j = 25/150$ °C
 $V_R = 350$ V
 $I_F = 150$ A
 $V_{GE} = \pm 15$ V

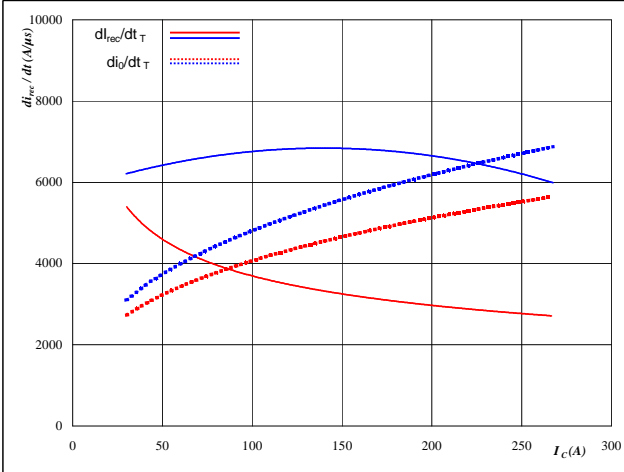


Buck

figure 17. FWD

Typical rate of fall of forward and reverse recovery current as a function of collector current

$dI_0/dt, dI_{rec}/dt = f(I_c)$

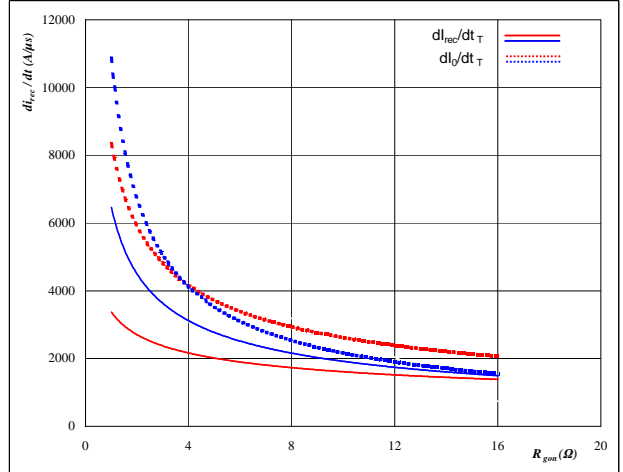


At
 $T_j = 25/150 \text{ } ^\circ\text{C}$
 $V_{CE} = 350 \text{ V}$
 $V_{GE} = \pm 15 \text{ V}$
 $R_{gon} = 4 \text{ } \Omega$

figure 18. FWD

Typical rate of fall of forward and reverse recovery current as a function of IGBT turn on gate resistor

$dI_0/dt, dI_{rec}/dt = f(R_{gon})$

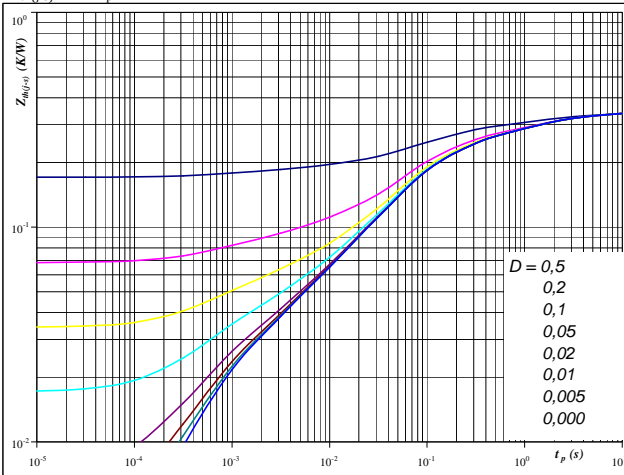


At
 $T_j = 25/150 \text{ } ^\circ\text{C}$
 $V_R = 350 \text{ V}$
 $I_F = 150 \text{ A}$
 $V_{GE} = \pm 15 \text{ V}$

figure 19. IGBT

IGBT transient thermal impedance as a function of pulse width

$Z_{th(j-s)} = f(t_p)$



At
 $D = t_p / T$
 $R_{th(j-s)} = 0,34 \text{ K/W}$

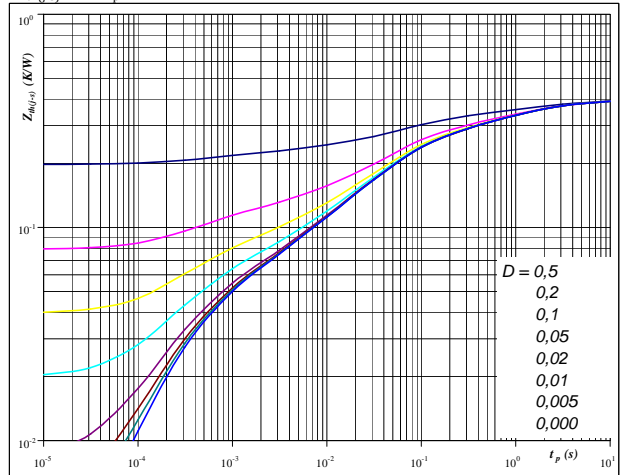
IGBT thermal model values

R (K/W)	Tau (s)
4,43E-02	3,55E+00
6,46E-02	8,58E-01
1,01E-01	1,36E-01
9,03E-02	4,30E-02
2,31E-02	4,39E-03
1,76E-02	6,24E-04

figure 20. FWD

FWD transient thermal impedance as a function of pulse width

$Z_{th(j-s)} = f(t_p)$



At
 $D = t_p / T$
 $R_{th(j-s)} = 0,39 \text{ K/W}$

FWD thermal model values

R (K/W)	Tau (s)
4,62E-02	3,80E+00
6,71E-02	9,22E-01
5,38E-02	2,23E-01
1,26E-01	5,05E-02
3,49E-02	1,17E-02
3,03E-02	2,42E-03

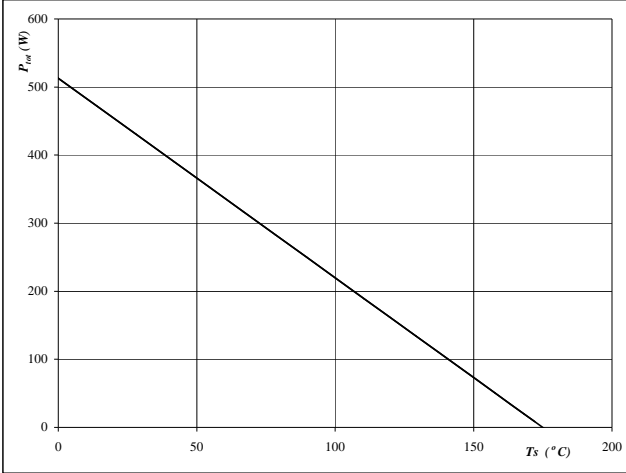


Buck

figure 21. IGBT

Power dissipation as a function of heatsink temperature

$P_{tot} = f(T_s)$

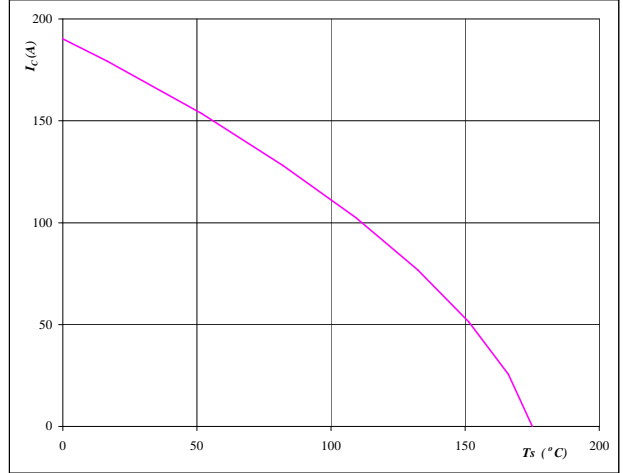


At
T_j = 175 °C

figure 22. IGBT

Collector current as a function of heatsink temperature

$I_C = f(T_s)$

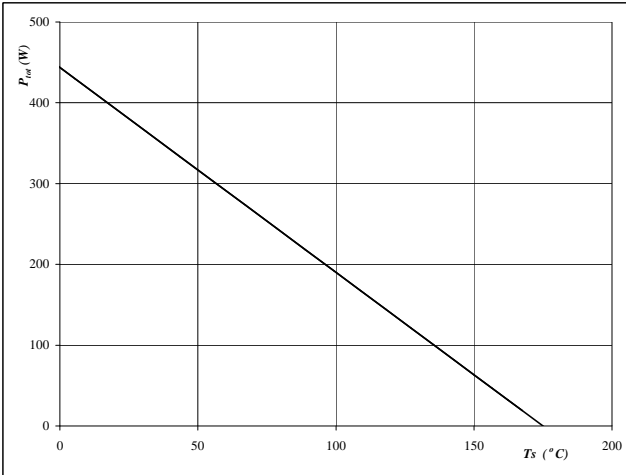


At
T_j = 175 °C
V_{GE} = 15 V

figure 23. FWD

Power dissipation as a function of heatsink temperature

$P_{tot} = f(T_s)$

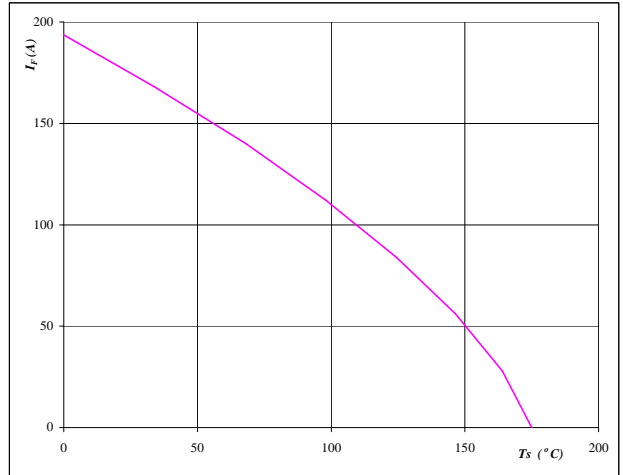


At
T_j = 175 °C

figure 24. FWD

Forward current as a function of heatsink temperature

$I_F = f(T_s)$



At
T_j = 175 °C

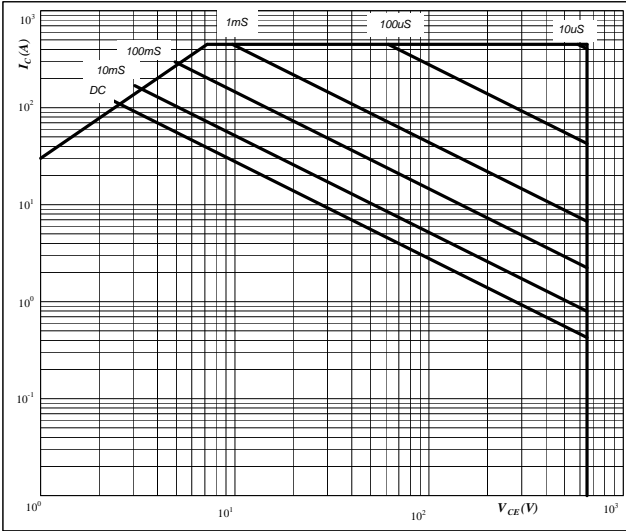


Buck

figure 25. IGBT

Safe operating area as a function of collector-emitter voltage

$I_C = f(V_{CE})$

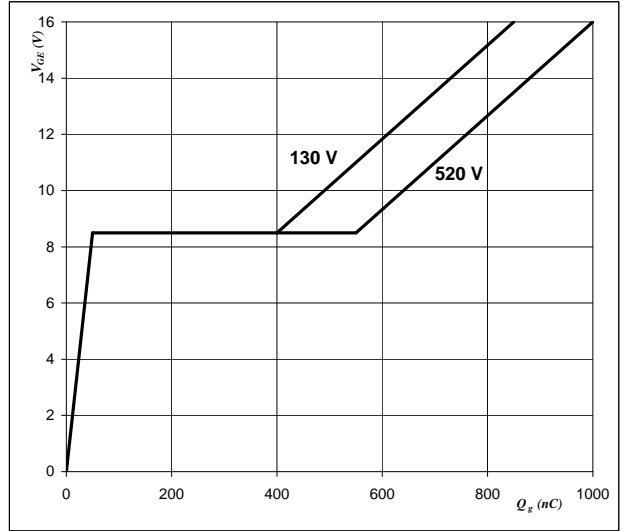


At
 D = single pulse
 T_s = 80 °C
 V_{GE} = ±15 V
 T_j = T_{jmax} °C

figure 26. IGBT

Gate voltage vs Gate charge

$V_{GE} = f(Q_g)$



At
 I_C = 150 A

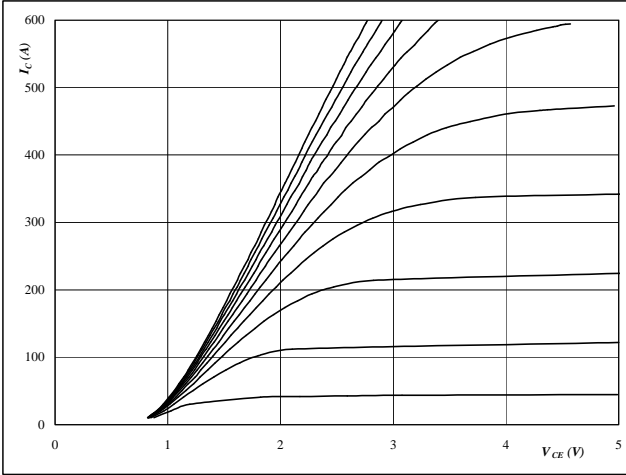


Boost

figure 1. IGBT

Typical output characteristics

$I_C = f(V_{CE})$



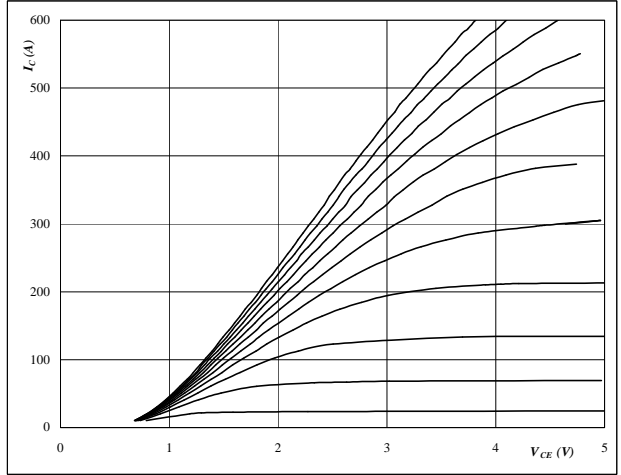
At

$t_p = 350 \mu s$
 $T_j = 25 \text{ } ^\circ C$
 V_{GE} from 7 V to 17 V in steps of 1 V

figure 2. IGBT

Typical output characteristics

$I_C = f(V_{CE})$



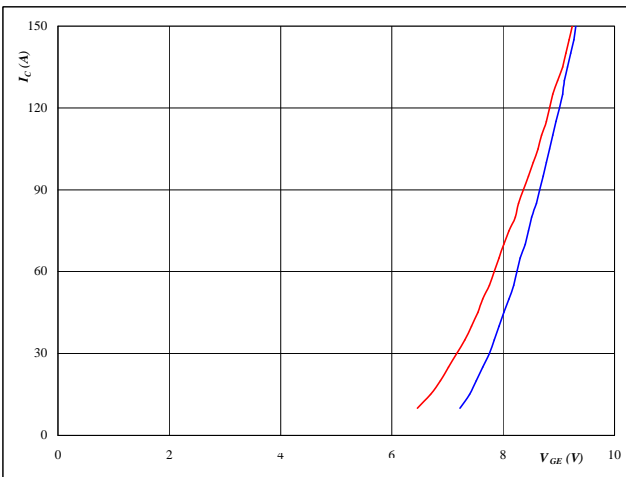
At

$t_p = 350 \mu s$
 $T_j = 150 \text{ } ^\circ C$
 V_{GE} from 7 V to 17 V in steps of 1 V

figure 3. IGBT

Typical transfer characteristics

$I_C = f(V_{GE})$



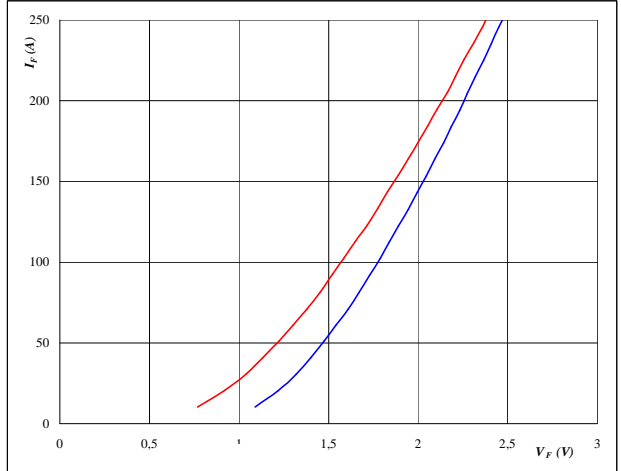
At

$t_p = 350 \mu s$
 $V_{CE} = 10 \text{ V}$

figure 4. FWD

Typical diode forward current as a function of forward voltage

$I_F = f(V_F)$



At

$t_p = 350 \mu s$

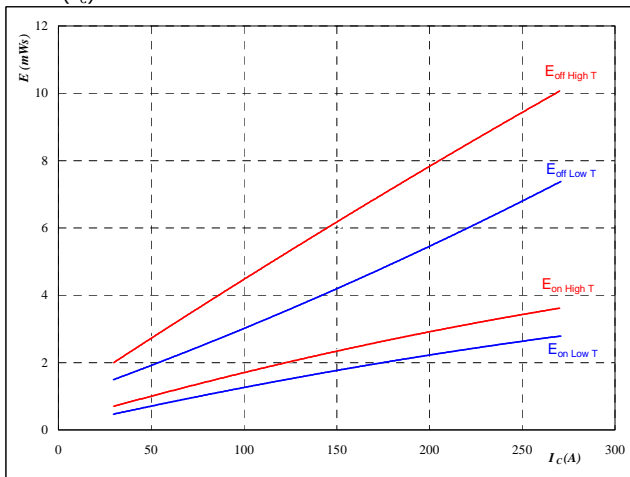


Boost

figure 5. IGBT

Typical switching energy losses as a function of collector current

$E = f(I_C)$



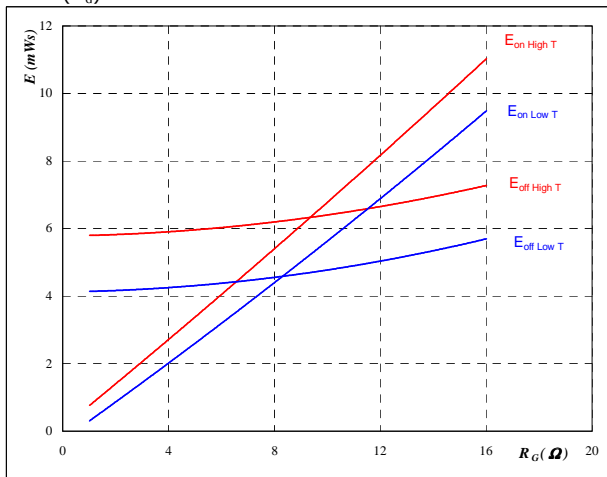
With an inductive load at

$T_j =$	25/150	°C
$V_{CE} =$	350	V
$V_{GE} =$	±15	V
$R_{gon} =$	4	Ω
$R_{goff} =$	4	Ω

figure 6. IGBT

Typical switching energy losses as a function of gate resistor

$E = f(R_G)$



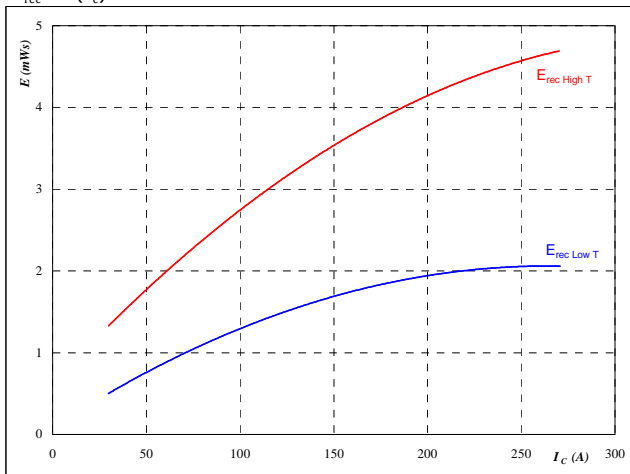
With an inductive load at

$T_j =$	25/150	°C
$V_{CE} =$	350	V
$V_{GE} =$	±15	V
$I_C =$	150	A

figure 7. FWD

Typical reverse recovery energy loss as a function of collector current

$E_{rec} = f(I_C)$



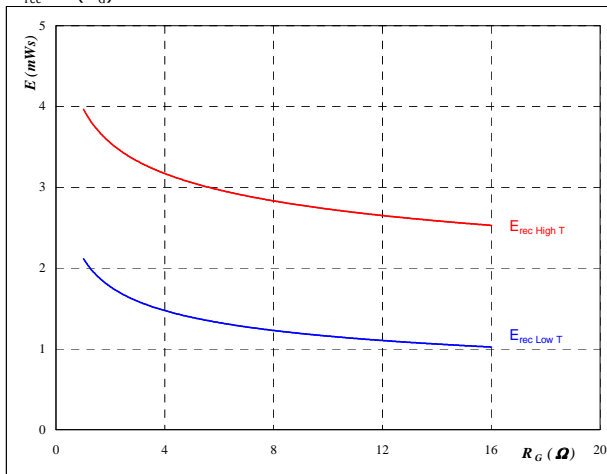
With an inductive load at

$T_j =$	25/150	°C
$V_{CE} =$	350	V
$V_{GE} =$	±15	V
$R_{gon} =$	4	Ω

figure 8. FWD

Typical reverse recovery energy loss as a function of gate resistor

$E_{rec} = f(R_G)$



With an inductive load at

$T_j =$	25/150	°C
$V_{CE} =$	350	V
$V_{GE} =$	±15	V
$I_C =$	150	A

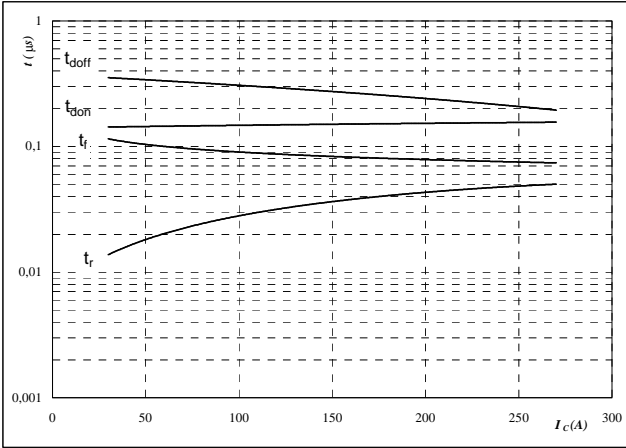


Boost

figure 9. IGBT

Typical switching times as a function of collector current

$t = f(I_C)$

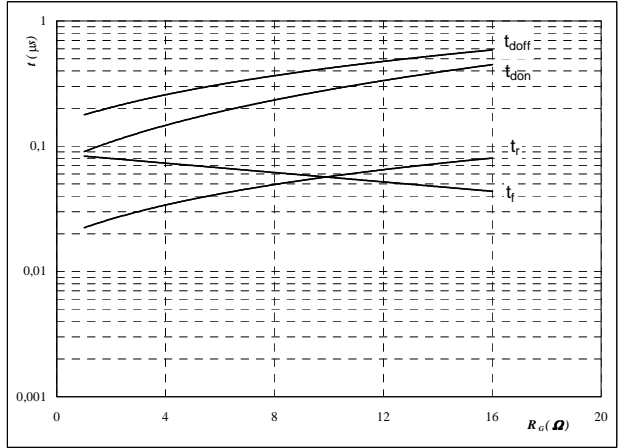


With an inductive load at
 $T_j = 150 \text{ } ^\circ\text{C}$
 $V_{CE} = 350 \text{ V}$
 $V_{GE} = \pm 15 \text{ V}$
 $R_{gon} = 4 \text{ } \Omega$
 $R_{goff} = 4 \text{ } \Omega$

figure 10. IGBT

Typical switching times as a function of gate resistor

$t = f(R_G)$

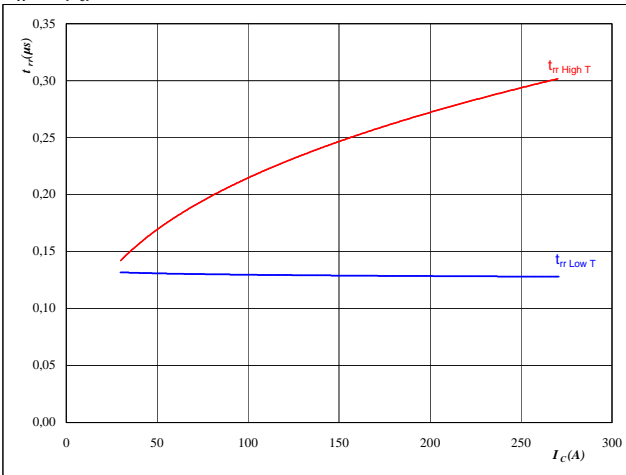


With an inductive load at
 $T_j = 150 \text{ } ^\circ\text{C}$
 $V_{CE} = 350 \text{ V}$
 $V_{GE} = \pm 15 \text{ V}$
 $I_C = 150 \text{ A}$

figure 11. FWD

Typical reverse recovery time as a function of collector current

$t_{rr} = f(I_C)$

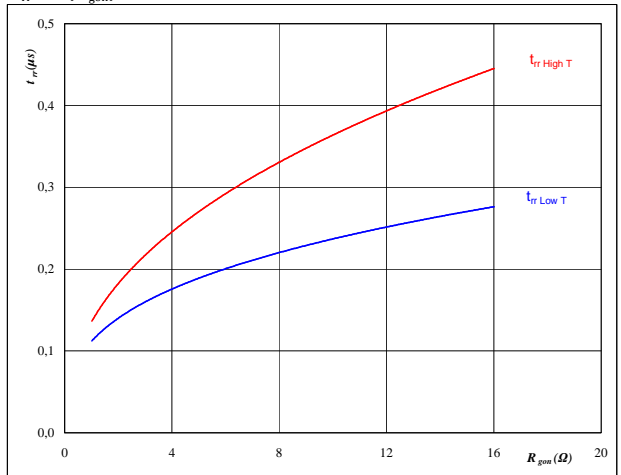


At
 $T_j = 25/150 \text{ } ^\circ\text{C}$
 $V_{CE} = 350 \text{ V}$
 $V_{GE} = \pm 15 \text{ V}$
 $R_{gon} = 4 \text{ } \Omega$

figure 12. FWD

Typical reverse recovery time as a function of IGBT turn on gate resistor

$t_{rr} = f(R_{gon})$



At
 $T_j = 25/150 \text{ } ^\circ\text{C}$
 $V_R = 350 \text{ V}$
 $I_F = 150 \text{ A}$
 $V_{GE} = \pm 15 \text{ V}$

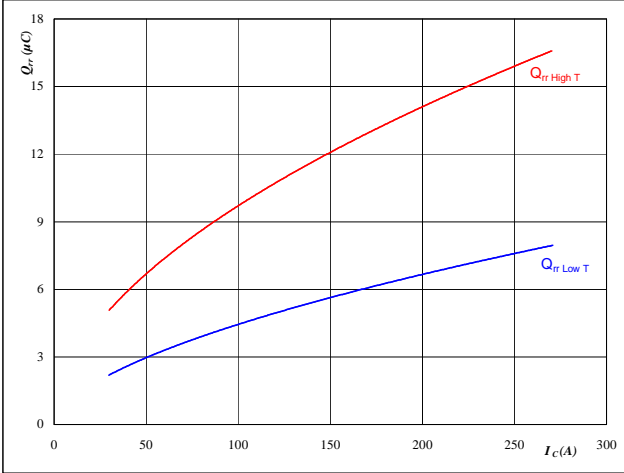


Boost

figure 13. FWD

Typical reverse recovery charge as a function of collector current

$$Q_{rr} = f(I_c)$$



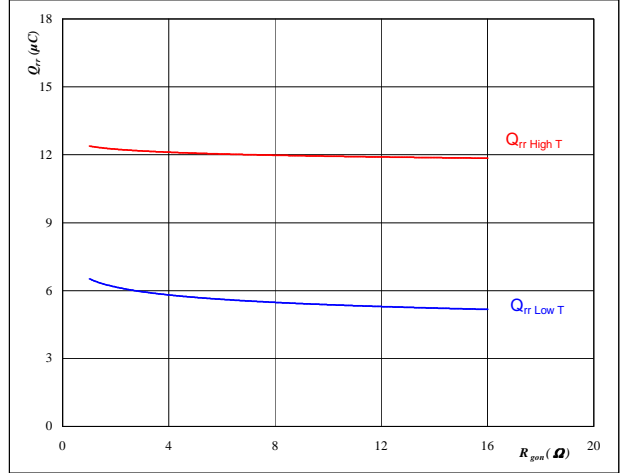
At

$T_j =$	25/150	°C
$V_{CE} =$	350	V
$V_{GE} =$	±15	V
$R_{gon} =$	4	Ω

figure 14. FWD

Typical reverse recovery charge as a function of IGBT turn on gate resistor

$$Q_{rr} = f(R_{gon})$$



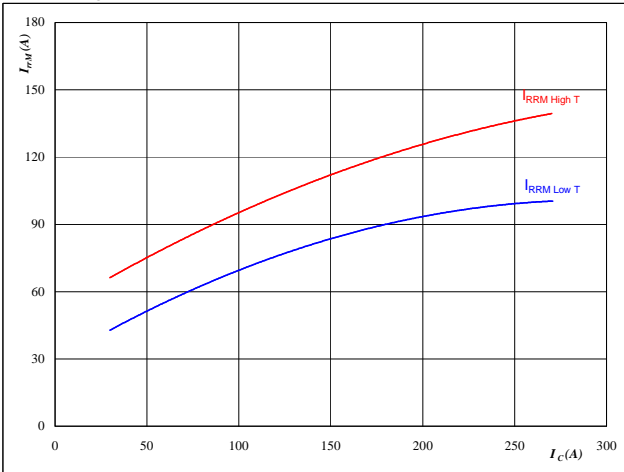
At

$T_j =$	25/150	°C
$V_R =$	350	V
$I_F =$	150	A
$V_{GE} =$	±15	V

figure 15. FWD

Typical reverse recovery current as a function of collector current

$$I_{RRM} = f(I_c)$$



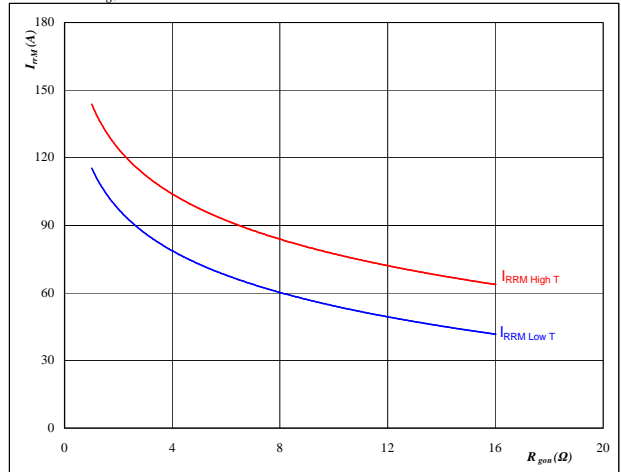
At

$T_j =$	25/150	°C
$V_{CE} =$	350	V
$V_{GE} =$	±15	V
$R_{gon} =$	4	Ω

figure 16. FWD

Typical reverse recovery current as a function of IGBT turn on gate resistor

$$I_{RRM} = f(R_{gon})$$



At

$T_j =$	25/150	°C
$V_R =$	350	V
$I_F =$	150	A
$V_{GE} =$	±15	V

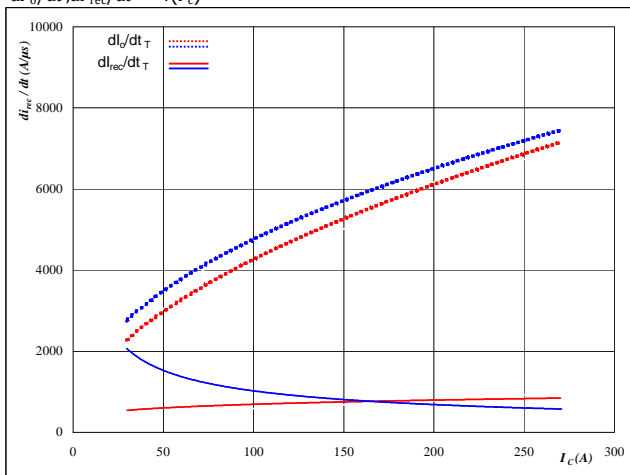


Boost

figure 17. FWD

Typical rate of fall of forward and reverse recovery current as a function of collector current

$$dI_0/dt, dI_{rec}/dt = f(I_c)$$

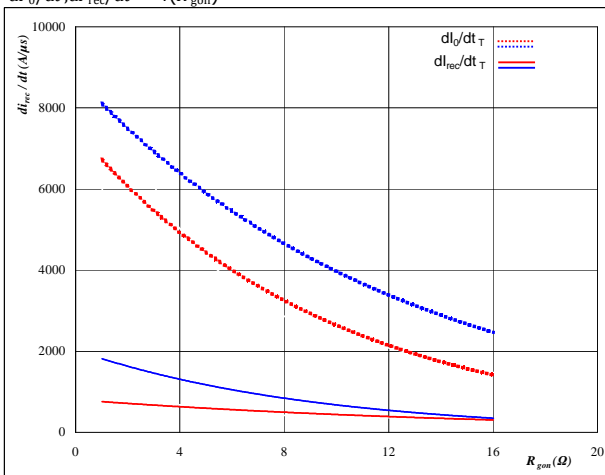


At
 $T_j = 25/150 \text{ } ^\circ\text{C}$
 $V_{CE} = 350 \text{ V}$
 $V_{GE} = \pm 15 \text{ V}$
 $R_{gon} = 4 \text{ } \Omega$

figure 18. FWD

Typical rate of fall of forward and reverse recovery current as a function of IGBT turn on gate resistor

$$dI_0/dt, dI_{rec}/dt = f(R_{gon})$$

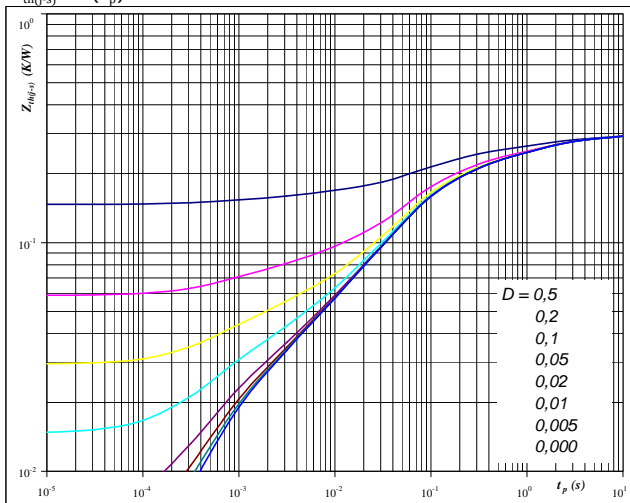


At
 $T_j = 25/150 \text{ } ^\circ\text{C}$
 $V_R = 350 \text{ V}$
 $I_F = 150 \text{ A}$
 $V_{GE} = \pm 15 \text{ V}$

figure 19. IGBT

IGBT transient thermal impedance as a function of pulse width

$$Z_{th(j-s)} = f(t_p)$$



At
 $D = t_p / T$
 $R_{th(j-s)} = 0,29 \text{ K/W}$

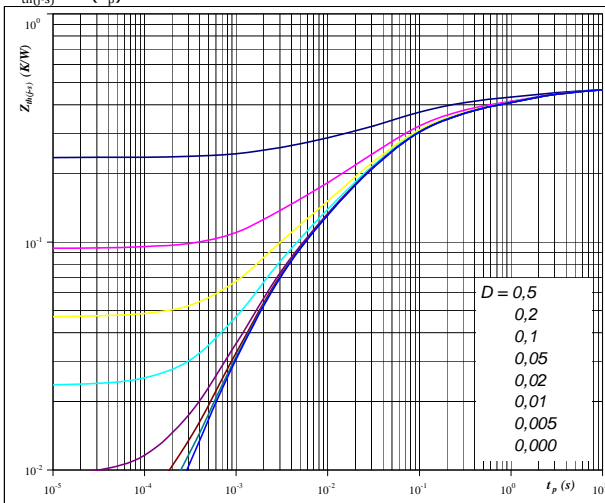
IGBT thermal model values

R (K/W)	Tau (s)
4,40E-02	2,95E+00
5,08E-02	7,93E-01
7,83E-02	1,41E-01
8,59E-02	4,33E-02
2,00E-02	3,83E-03
1,46E-02	5,99E-04

figure 20. FWD

FWD transient thermal impedance as a function of pulse width

$$Z_{th(j-s)} = f(t_p)$$



At
 $D = t_p / T$
 $R_{th(j-s)} = 0,47 \text{ K/W}$

FWD thermal model values

R (K/W)	Tau (s)
4,73E-02	4,12E+00
6,76E-02	9,18E-01
1,01E-01	1,37E-01
1,41E-01	3,83E-02
6,28E-02	8,98E-03
4,92E-02	1,99E-03

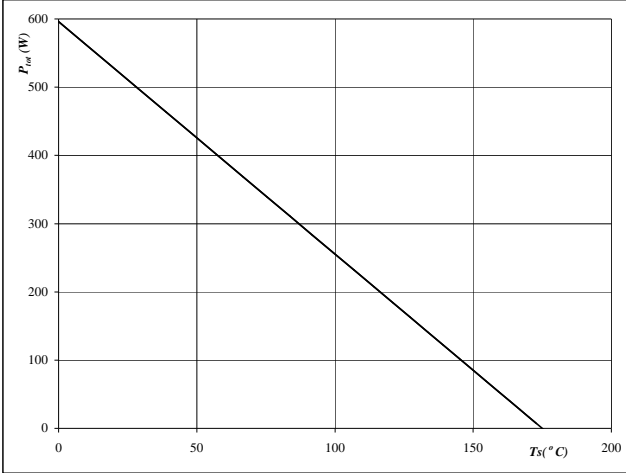


Boost

figure 21. IGBT

Power dissipation as a function of heatsink temperature

$P_{tot} = f(T_s)$

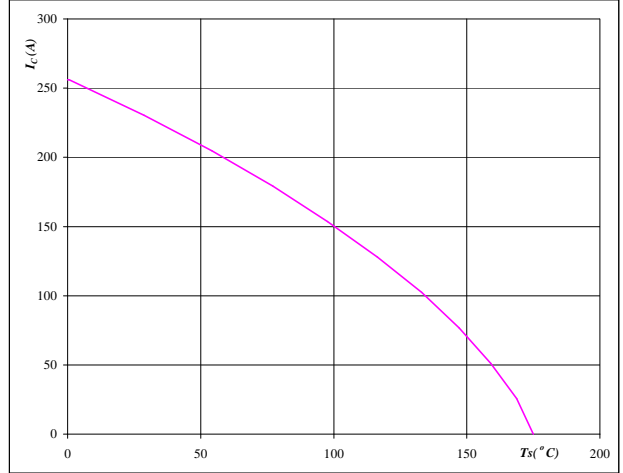


At
T_j = 175 °C

figure 22. IGBT

Collector current as a function of heatsink temperature

$I_C = f(T_s)$

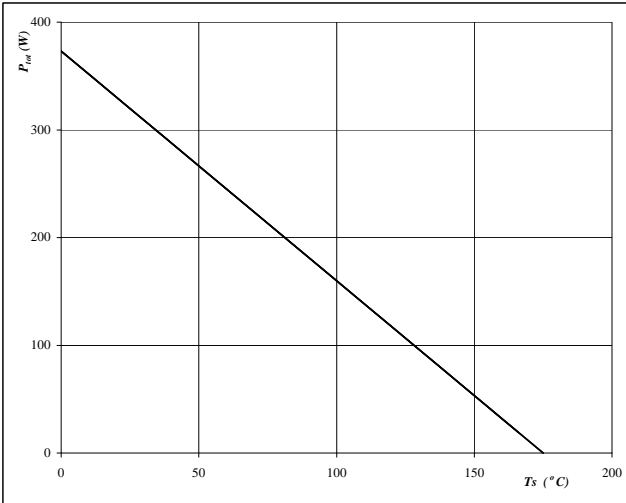


At
T_j = 175 °C
V_{GE} = 15 V

figure 23. FWD

Power dissipation as a function of heatsink temperature

$P_{tot} = f(T_s)$

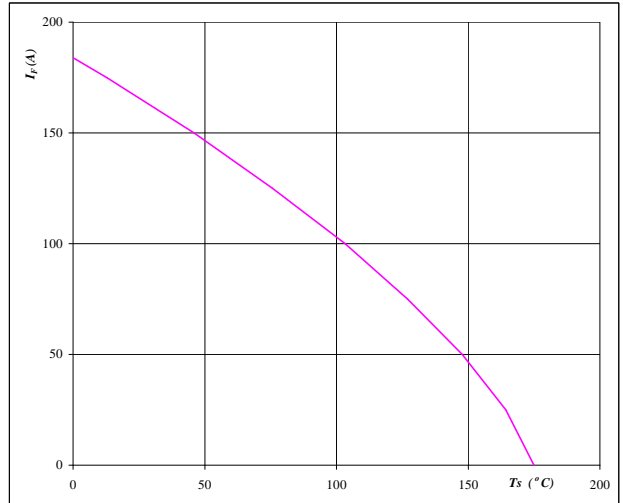


At
T_j = 175 °C

figure 24. FWD

Forward current as a function of heatsink temperature

$I_F = f(T_s)$



At
T_j = 175 °C

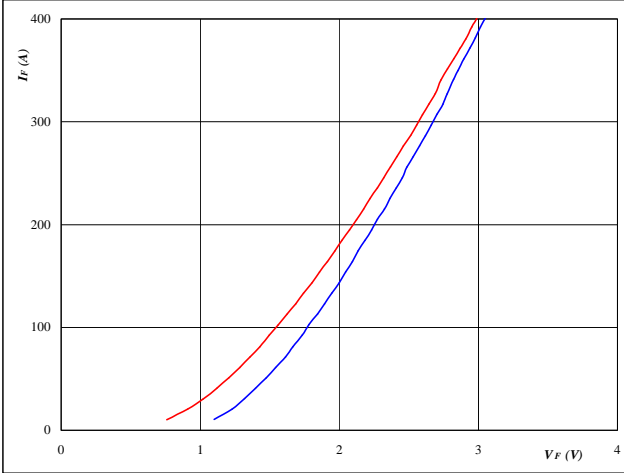


Boost inv. Diode

figure 25. Boost Inverse Diode

Typical diode forward current as a function of forward voltage

$$I_F = f(V_F)$$

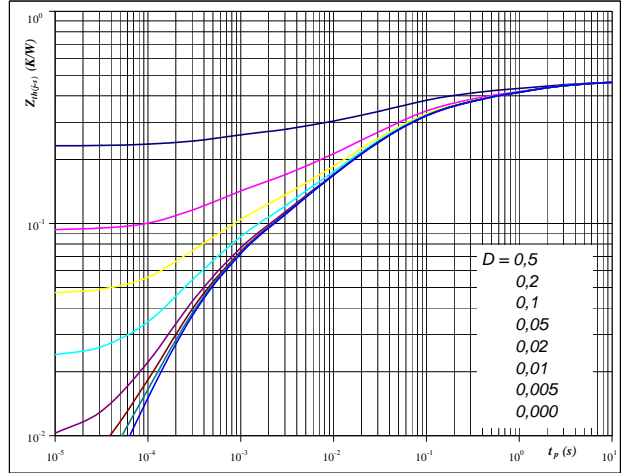


At
 $t_p = 250 \mu s$

figure 26. Boost Inverse Diode

Diode transient thermal impedance as a function of pulse width

$$Z_{th(j-s)} = f(t_p)$$

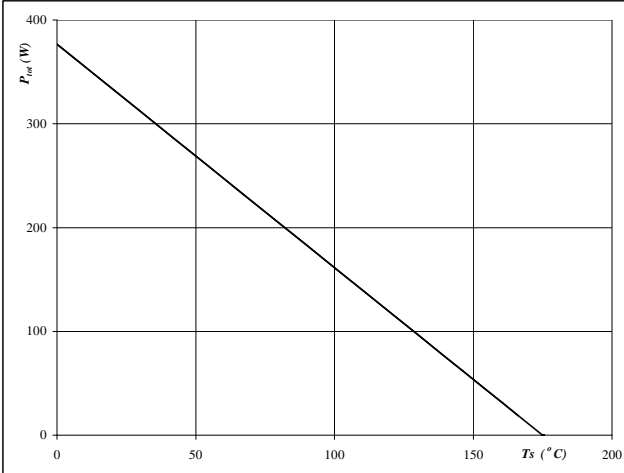


At
 $D = t_p / T$
 $R_{th(j-s)} = 0,46 \text{ K/W}$

figure 27. Boost Inverse Diode

Power dissipation as a function of heatsink temperature

$$P_{tot} = f(T_s)$$

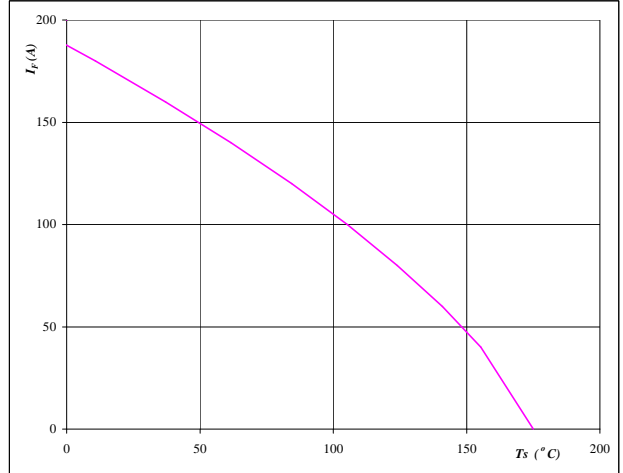


At
 $T_j = 175 \text{ } ^\circ C$

figure 28. Boost Inverse Diode

Forward current as a function of heatsink temperature

$$I_F = f(T_s)$$



At
 $T_j = 175 \text{ } ^\circ C$

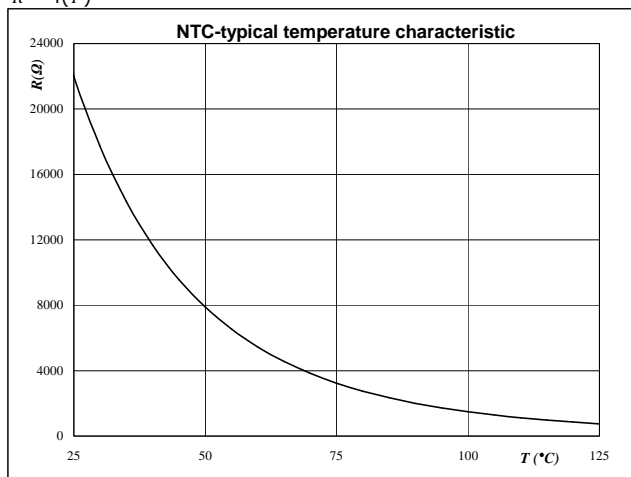


Thermistor

figure 1. Thermistor

**Typical NTC characteristic
as a function of temperature**

$$R = f(T)$$





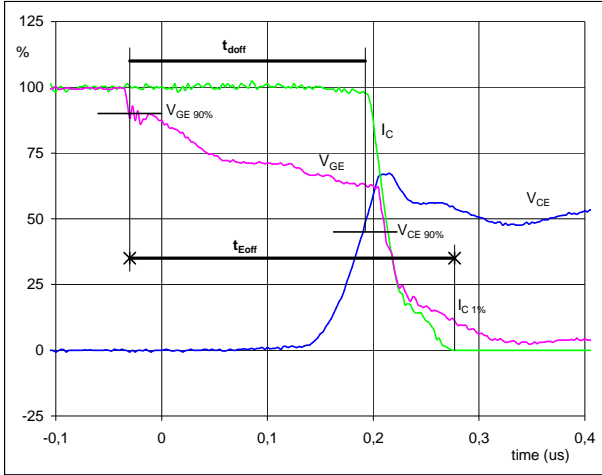
Switching Definitions BUCK

General conditions

T_j	=	150 °C
R_{gon}	=	4 Ω
R_{goff}	=	4 Ω

figure 1. IGBT

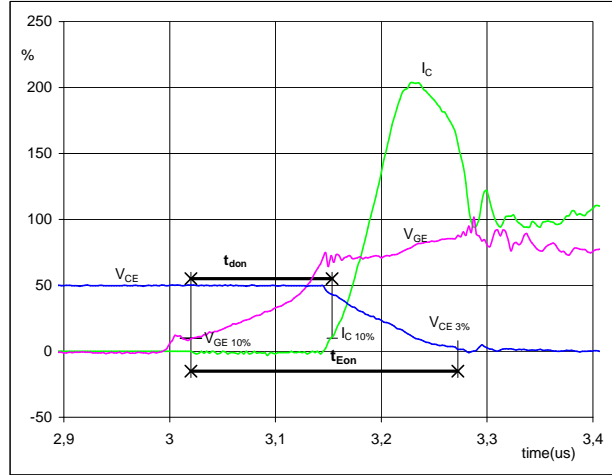
Turn-off Switching Waveforms & definition of t_{doff} , t_{Eoff}
(t_{Eoff} = integrating time for E_{off})



V_{GE} (0%) =	-15	V
V_{GE} (100%) =	15	V
V_C (100%) =	700	V
I_C (100%) =	150	A
t_{doff} =	0,22	μs
t_{Eoff} =	0,31	μs

figure 2. IGBT

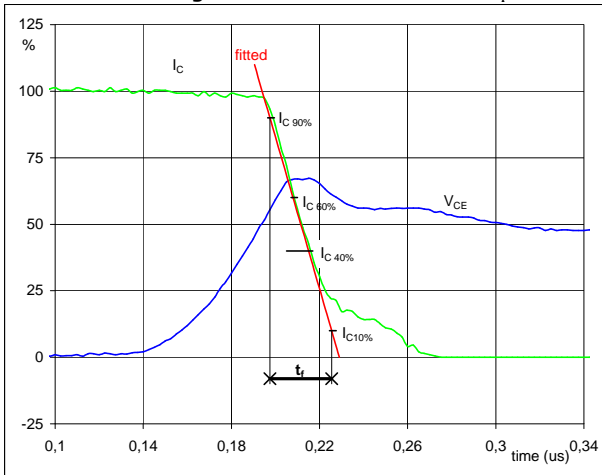
Turn-on Switching Waveforms & definition of t_{don} , t_{Eon}
(t_{Eon} = integrating time for E_{on})



V_{GE} (0%) =	-15	V
V_{GE} (100%) =	15	V
V_C (100%) =	700	V
I_C (100%) =	150	A
t_{don} =	0,15	μs
t_{Eon} =	0,25	μs

figure 3. IGBT

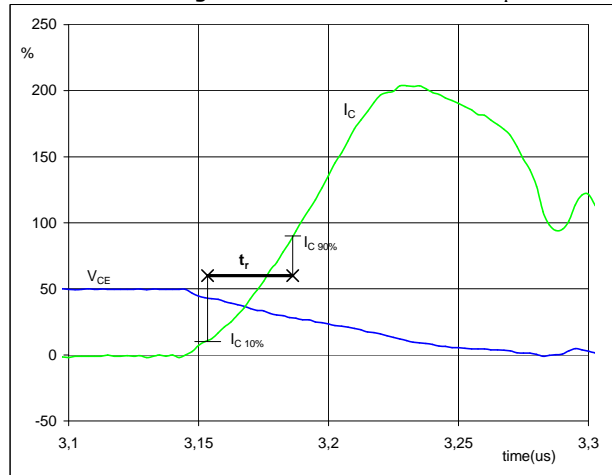
Turn-off Switching Waveforms & definition of t_f



V_C (100%) =	700	V
I_C (100%) =	150	A
t_f =	0,03	μs

figure 4. IGBT

Turn-on Switching Waveforms & definition of t_r

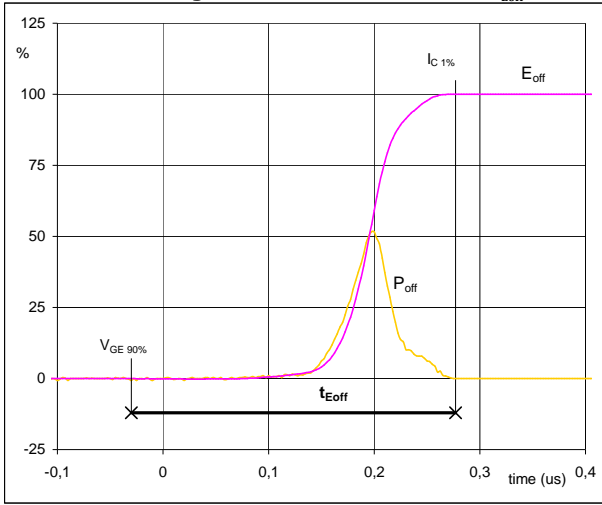


V_C (100%) =	700	V
I_C (100%) =	150	A
t_r =	0,03	μs



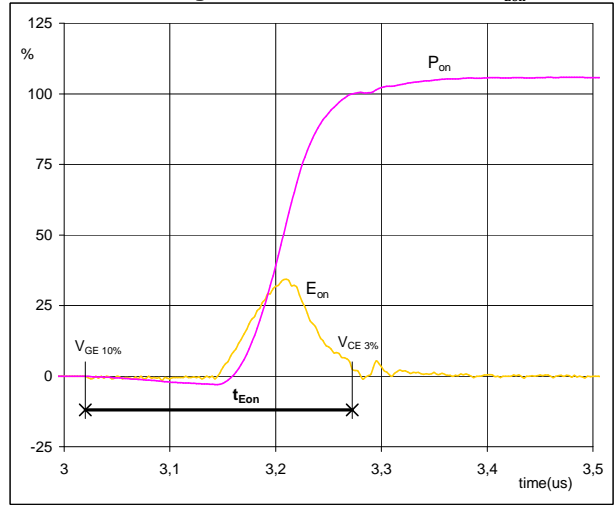
Switching Definitions BUCK

figure 5. IGBT
Turn-off Switching Waveforms & definition of t_{Eoff}



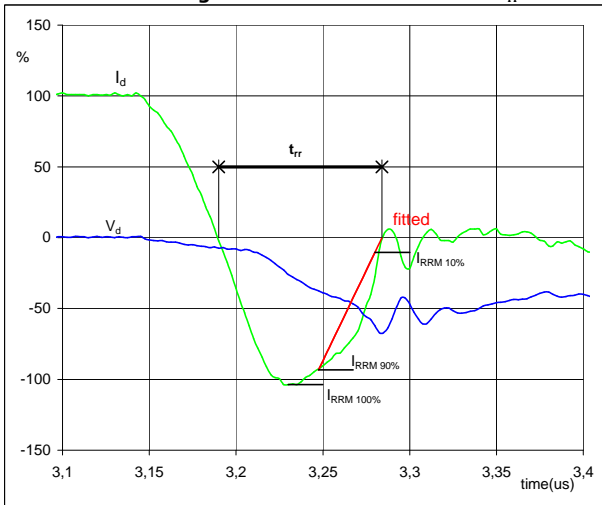
$P_{off} (100\%) = 105 \text{ kW}$
 $E_{off} (100\%) = 2,68 \text{ mJ}$
 $t_{Eoff} = 0,31 \text{ } \mu\text{s}$

figure 6. IGBT
Turn-on Switching Waveforms & definition of t_{Eon}



$P_{on} (100\%) = 105 \text{ kW}$
 $E_{on} (100\%) = 2,45 \text{ mJ}$
 $t_{Eon} = 0,25 \text{ } \mu\text{s}$

figure 8. FWD
Turn-off Switching Waveforms & definition of t_{rr}



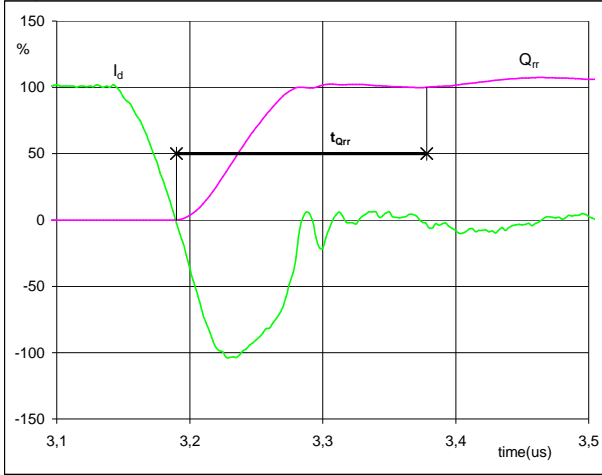
$V_d (100\%) = 700 \text{ V}$
 $I_d (100\%) = 150 \text{ A}$
 $I_{RRM} (100\%) = -157 \text{ A}$
 $t_{rr} = 0,10 \text{ } \mu\text{s}$



Switching Definitions BUCK

figure 9. FWD

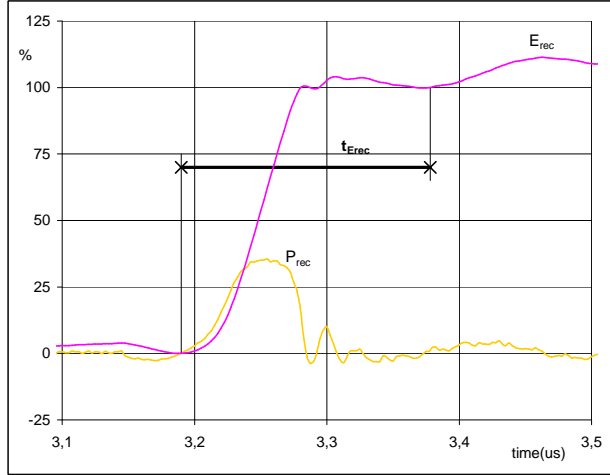
Turn-on Switching Waveforms & definition of t_{Qrr}
(t_{Qrr} = integrating time for Q_{rr})



I_d (100%) =	150	A
Q_{rr} (100%) =	9,91	μC
t_{Qrr} =	0,19	μs

figure 10. FWD

Turn-on Switching Waveforms & definition of t_{Erec}
(t_{Erec} = integrating time for E_{rec})



P_{rec} (100%) =	105,00	kW
E_{rec} (100%) =	2,07	mJ
t_{Erec} =	0,19	μs



Ordering Code and Marking - Outline - Pinout

Ordering Code & Marking							
Version			Ordering Code				
with thermal paste 12mm housing with Press-fit pins			10-PY07NIB150SG-M136F38Y-/3/				
	Text	VIN	Date code	Name&Ver	UL	Lot	Serial
		VIN	WWYY	NNNNVV	UL	LLLL	SSSS
	Datamatrix	Type&Ver	Lot number	Serial	Date code		
		TTTTTV	LLLL	SSSS	WWYY		

Outline

Pin table			
Pin	X	Y	Function
1	52,2	6,9	NTC1
2	52,2	0	NTC2
3	36,2	6,75	E37
4	33,2	7,9	G3
5	33,2	4,9	G7
6	9,2	5,75	E48
7	6,2	6,9	G4
8	6,2	3,9	G8
9	2,7	0	DC-
10	0	0	DC-
11	2,7	2,7	DC-
12	0	2,7	DC-
13	2,7	5,4	DC-
14	0	5,4	DC-
15	2,7	12,75	GND
16	0	12,75	GND
17	2,7	15,45	GND
18	0	15,45	GND
19	2,7	22,8	DC+
20	0	22,8	DC+
21	2,7	25,5	DC+
22	0	25,5	DC+
23	2,7	28,2	DC+
24	0	28,2	DC+
25	18,3	22,45	E15
26	21,3	21,3	G5
27	21,3	24,3	G1
28	43	22,15	E26
29	46	21	G6
30	46	24	G2
31	52,2	20,1	OUT
32	49,5	22,8	OUT
33	52,2	22,8	OUT
34	49,5	25,5	OUT
35	52,2	25,5	OUT
36	49,5	28,2	OUT
37	52,2	28,2	OUT

center of press-fit pinhead
for connection parameter see the handling instruction

29,5 ±0,1
16,2 ±0,5

26,1

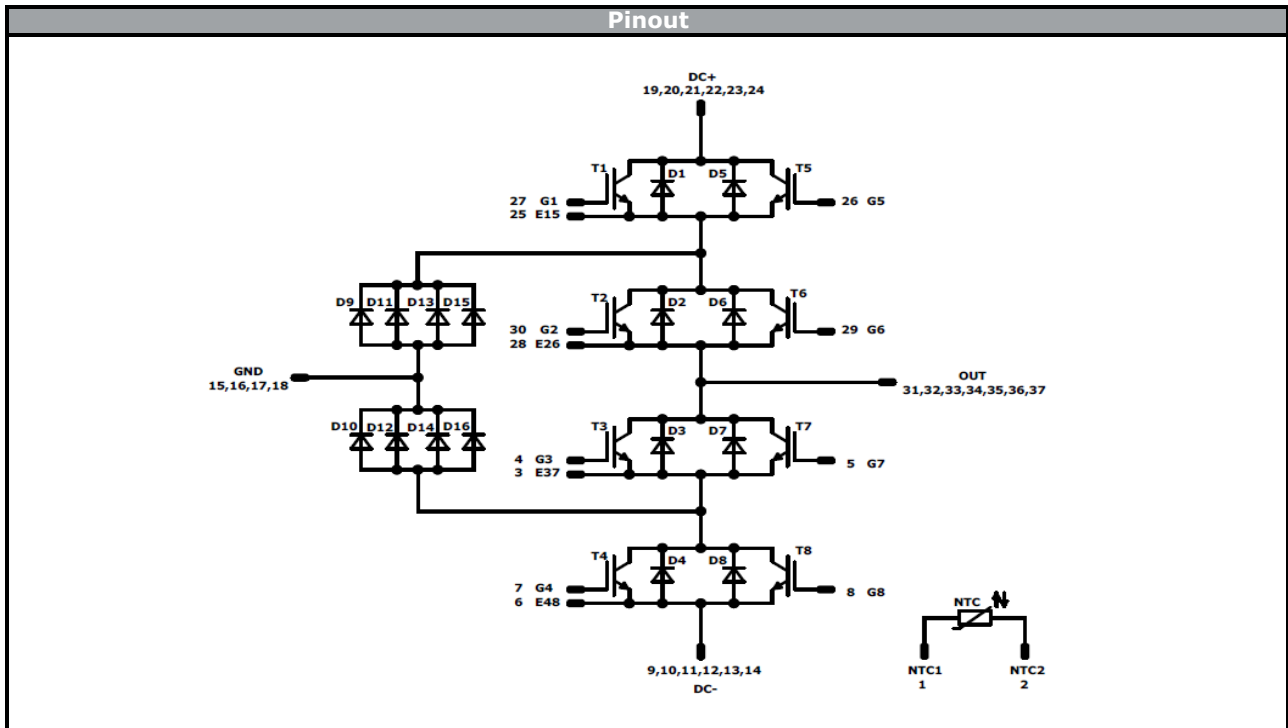
16,1

X
Y

Tolerance of pinpositions ±0,5mm at the end of pins
Dimension of coordinate axis is only offset without tolerance



Ordering Code and Marking - Outline - Pinout




Identification					
ID	Component	Voltage	Current	Function	Comment
T1,T4,T5,T8	IGBT	650 V	75 A	Buck IGBT	
D9,D10,D11,D12 D13,D14,D15,D16	FWD	650 V	40 A	Buck Diode	
T2,T3,T6,T7	IGBT	600 V	75 A	Boost IGBT	
D1,D4,D5,D8	FWD	650 V	50 A	Boost Diode	
D2,D3,D6,D7	FWD	600 V	50 A	Boost Inverse Diode	
NTC	Thermistor			Thermistor	



Packaging instruction			
Standard packaging quantity (SPQ)	100	>SPQ Standard	<SPQ Sample

Handling instruction
Handling instructions for <i>flow</i> 1 packages see vincotech.com website.

Package data
Package data for <i>flow</i> 1 packages see vincotech.com website.

UL recognition and file number
This device is certified according to UL 1557 standard, UL file number E192116. For more information see vincotech.com website. 

Document No.:	Date:	Modification:	Pages
10-PY07NIB150SG-M136F38Y-D2-14	21 Jul. 2016	New brand, new outline	all

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2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.